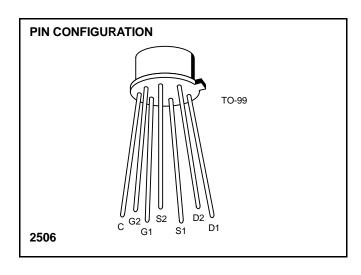
Dual P-Channel Enhancement Mode MOSFET General Purpose Amplifier



3N190/3N191

FEATURES

- Very High Input Impedance
- High Gate Breakdown 3N190-3N191
- Low Capacitance



ABSOLUTE MAXIMUM RATINGS

 $(T_A = 25^{\circ}C \text{ unless otherwise specified})$

Drain-Source or Drain-Gate Voltage (Note 1)
3N190, 3N191
Transient Gate-Source Voltage (Note 1 and 2) ±125V
Gate-Gate Voltage
Drain Current (Note 1) 50mA
Storage Temperature65°C to +200°C
Operating Temperature
Lead Temperature (Soldering, 10sec) +300°C
Power Dissipation
One Side
Both Sides
Total Derating above 25°C4.2mW/°C

NOTE: Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions above those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ORDERING INFORMATION

Part	Package	Temperature Range
	Hermetic TO-99 Sorted Chips in Carriers	-55°C to +150°C -55°C to +150°C

ELECTRICAL CHARACTERISTICS (T_A = 25°C and V_{BS} = 0 unless otherwise specified)

SYMBOL	PARAMETER	3N190/91		LINITE	TEST CONDITIONS		
STIVIBUL		MIN	MAX	UNITS	TEST CONDITIONS		
I _{GSSR}	Gate Reverse Current		10		V _{GS} = 40V		
laaa	Gate Forward Current		-10	pА	V _{GS} = -40V		
IGSSF	Gate Forward Current		-25			$T_A = +125^{\circ}C$	
BV _{DSS}	Drain-Source Breakdown Voltage	-40			$I_D = -10\mu A$		
BV _{SDS}	Source-Drain Breakdown Voltage	-40			$I_S = -10\mu A$, $V_{BD} = 0$		
.,	Thursday I d Make a s	-2.0	-5.0		$V_{DS} = -15V$, $I_{D} = -10\mu A$		
V _{GS(th)}	Threshold Voltage	-2.0	-5.0	V	$V_{DS} = V_{GS}$, $I_D = -10\mu A$		
V _{GS}	Gate Source Voltage	-3.0	-6.5		V _{DS} = -15V, I _D = -500μA		
I _{DSS}	Zero Gate Voltage Drain Current		-200		V _{DS} = -15V		
I _{SDS}	Source Drain Current		-400	1	$V_{SD} = -15V, V_{DB} = 0$		
r _{DS(on)}	Drain-Source on Resistance		300	ohms	$V_{DS} = -20V, I_{D} = -100\mu A$		
I _{D(on)}	On Drain Current	-5.0	-30.0	mA	V _{DS} = -15V, V _{GS} = -10V		



ELECTRICAL CHARACTERISTICS (Continued) (T_A = 25°C and V_{BS} = 0 unless otherwise specified)

SYMBOL	PARAMETER	3N190/91		UNITS	TEST CONDITIONS		
STIVIBUL		MIN	MAX	UNITS	TEST CONDITIONS		
g fs	Forward Transconductance (Note 3)	1500	4000	μS		f = 1kHz	
Yos	Output Admittance		300	μΟ		I = IRIIZ	
Ciss	Input Capacitance Output Shorted (Note 5)		4.5		$V_{DS} = -15V, I_{D} = -10mA$		
Crss	Reverse Transfer Capacitance (Note 5)		1.0	pF		f = 1MHz	
Coss	Output Capacitance Input Shorted (Note 5)		3.0				

SWITCHING CHARACTERISTICS ($T_A = 25^{\circ}C$ and $V_{BS} = 0$ unless otherwise specified)

SYMBOL	PARAMETER	MIN	MAX	UNITS	TEST CONDITIONS
t _{d(on)}	Turn On Delay Time		15		
tr	Rise Time		30	ns	$V_{DD} = -15V$, $I_D = -10mA$, $R_G = R_L = 1.4k\Omega$ (Note 5)
t _{off}	Turn Off Time		50		

MATCHING CHARACTERISTICS ($T_A = 25^{\circ}C$ and $V_{BS} = 0$ unless otherwise specified) 3N188 and 3N190

SYMBOL	PARAMETER	MIN	MAX	UNITS	TEST CONDITIONS
Y _{fs1} / Y _{fs2}	Forward Transconductance Ratio	0.85	1.0		$V_{DS} = -15V$, $I_{D} = -500\mu A$, $f = 1kHz$
V _{GS1-2}	Gate Source Threshold Voltage Differential		100	mV	V _{DS} = -15V, I _D = -500μA
$\frac{\Delta V_{GS1-2}}{\Delta T}$	Gate Source Threshold Voltage Differential Change with Temperature (Note 4)		100	μV/°C	$V_{DS} = -15V$, $I_{D} = -500\mu A$, $T = -55^{\circ}C$ to $+25^{\circ}C$
$\frac{\Delta V_{GS1-2}}{\Delta T}$	Gate Source Threshold Voltage Differential Change with Temperature (Note 4)		100	μV/°C	$V_{DS} = -15V$, $I_{D} = -500\mu A$ $T = +25^{\circ}C$ to $+125^{\circ}C$

NOTES: 1. Per transistor.

- Per transistor.
 Approximately doubles for every 10°C increase in T_A.
 Pulse test duration = 300μs; duty cycle ≤3%.
 Measured at end points, T_A and T_B.
 For design reference only, not 100% tested.